

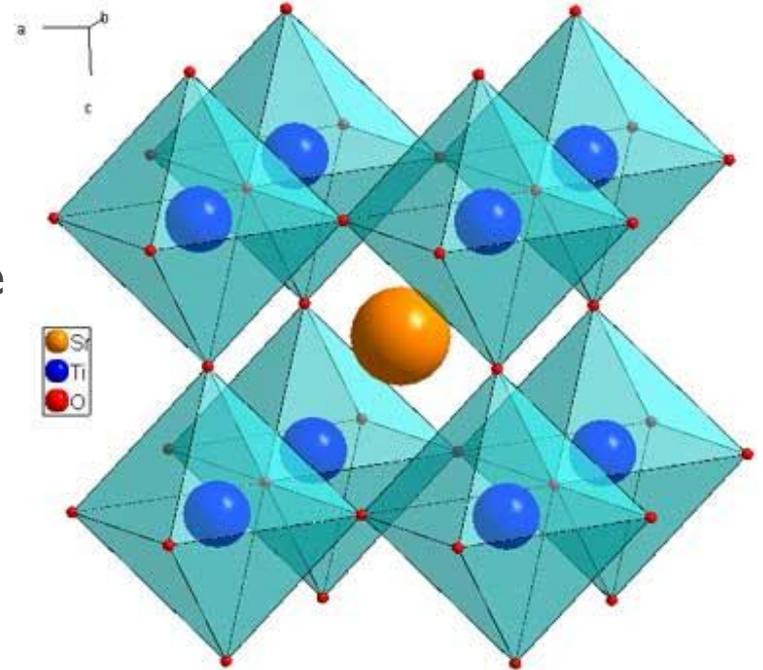
# **Direct imaging of SrTiO<sub>3</sub> surface reconstructions**

M. Kruize  
Journal club 6-11-2012

# SrTiO<sub>3</sub> crystal structure

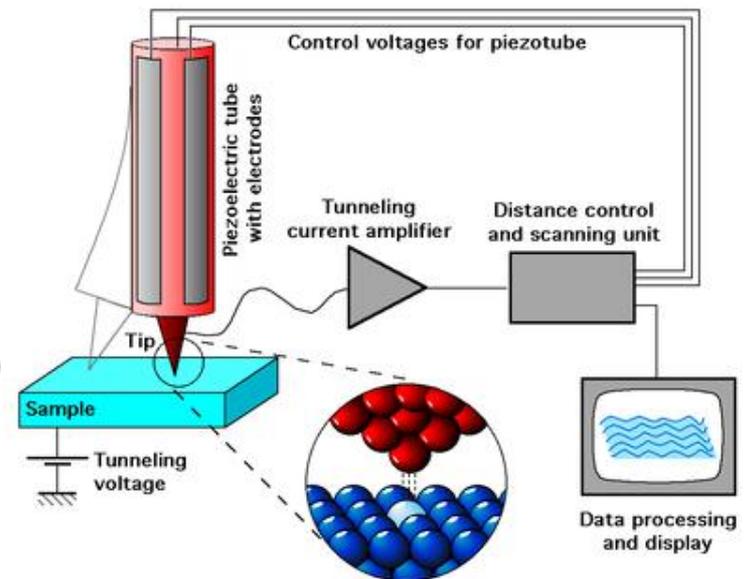
---

- ▶ Cubic perovskite 0.3905 nm lattice parameter
- ▶ (001) SrO-TiO<sub>2</sub> planes
  - ▶ Comparable thermodynamic stability
- ▶ Reconstruction surface
  - ▶ Ordered surface defect
  - ▶ Oxygen pressure and temperature related
- ▶ Many reported reconstructions of the 001 surface: (1x1), (2x1), c(4x4), c(4x2), c(6x2), (4x4) etc..

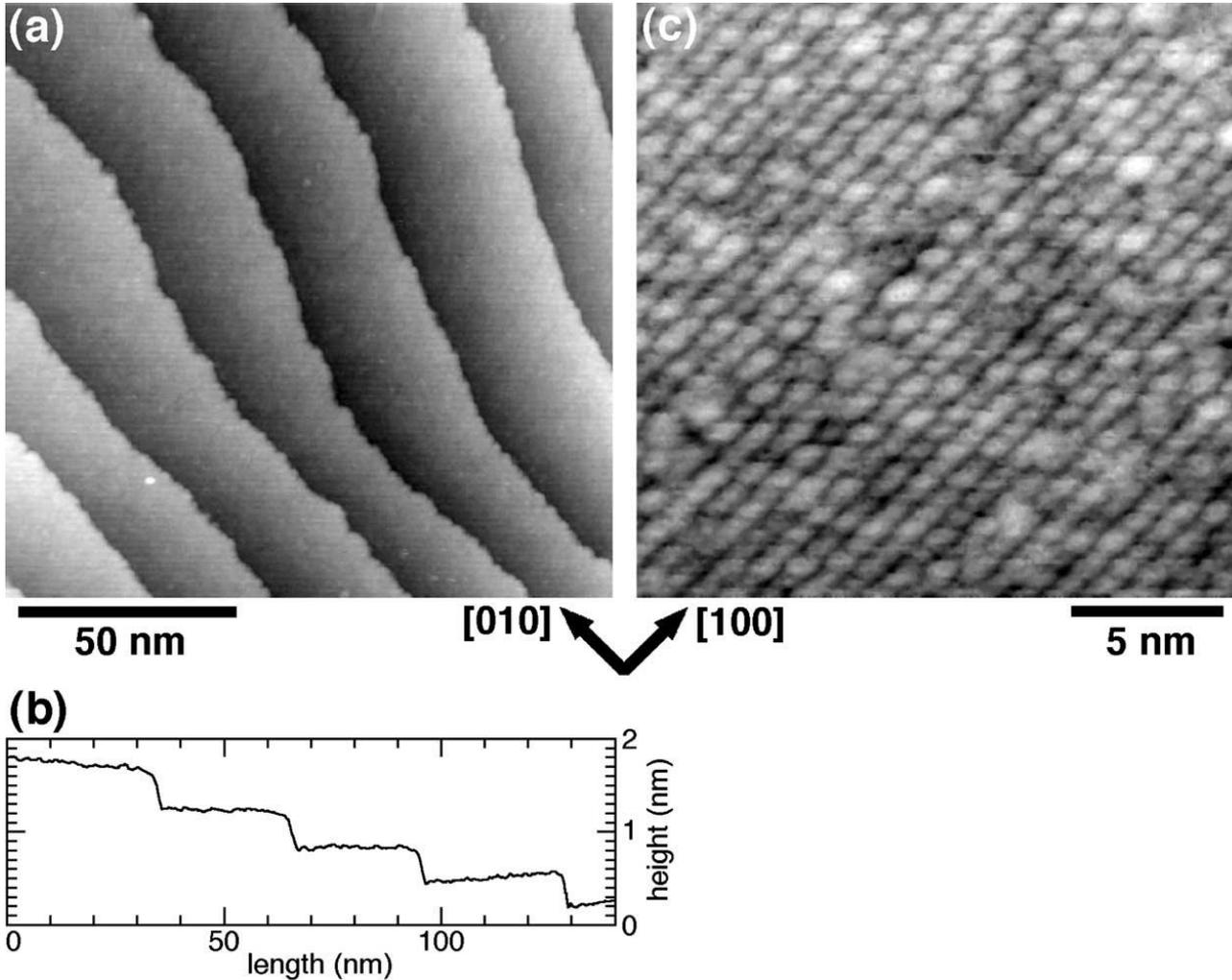


# Scanning Tunneling Microscopy

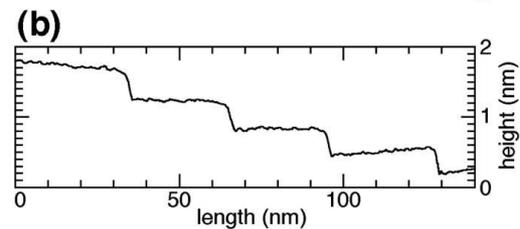
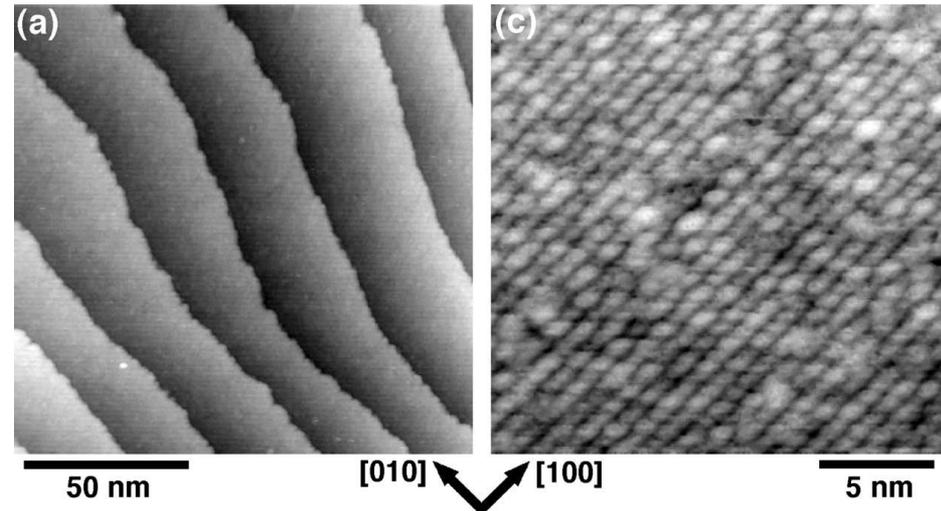
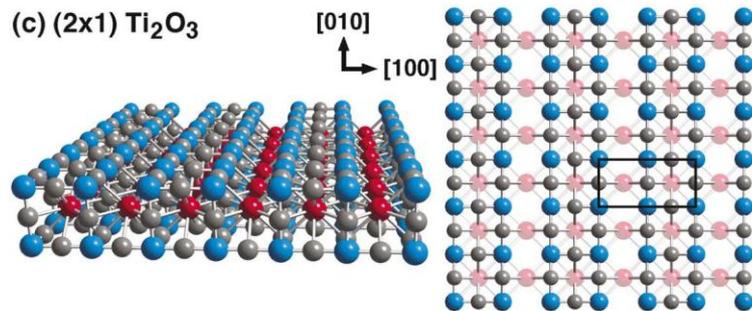
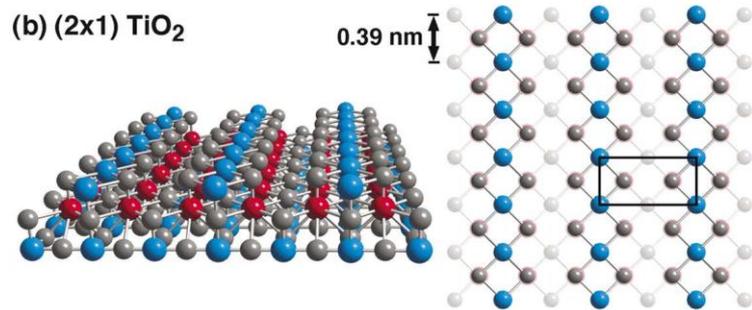
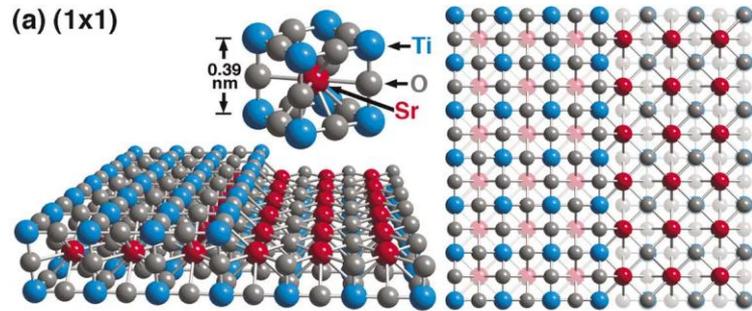
- ▶ Conducting surface
  - ▶ Nb SrTiO<sub>3</sub>
- ▶ (1x1) 30 min @600 °C (10<sup>-8</sup> Pa)
- ▶ (2x1) 30 min between 600-800 °C (10<sup>-8</sup> Pa)
- ▶ c(4x4) 20 min @1100°C (10<sup>-8</sup> Pa)



# (2x1) surface reconstruction

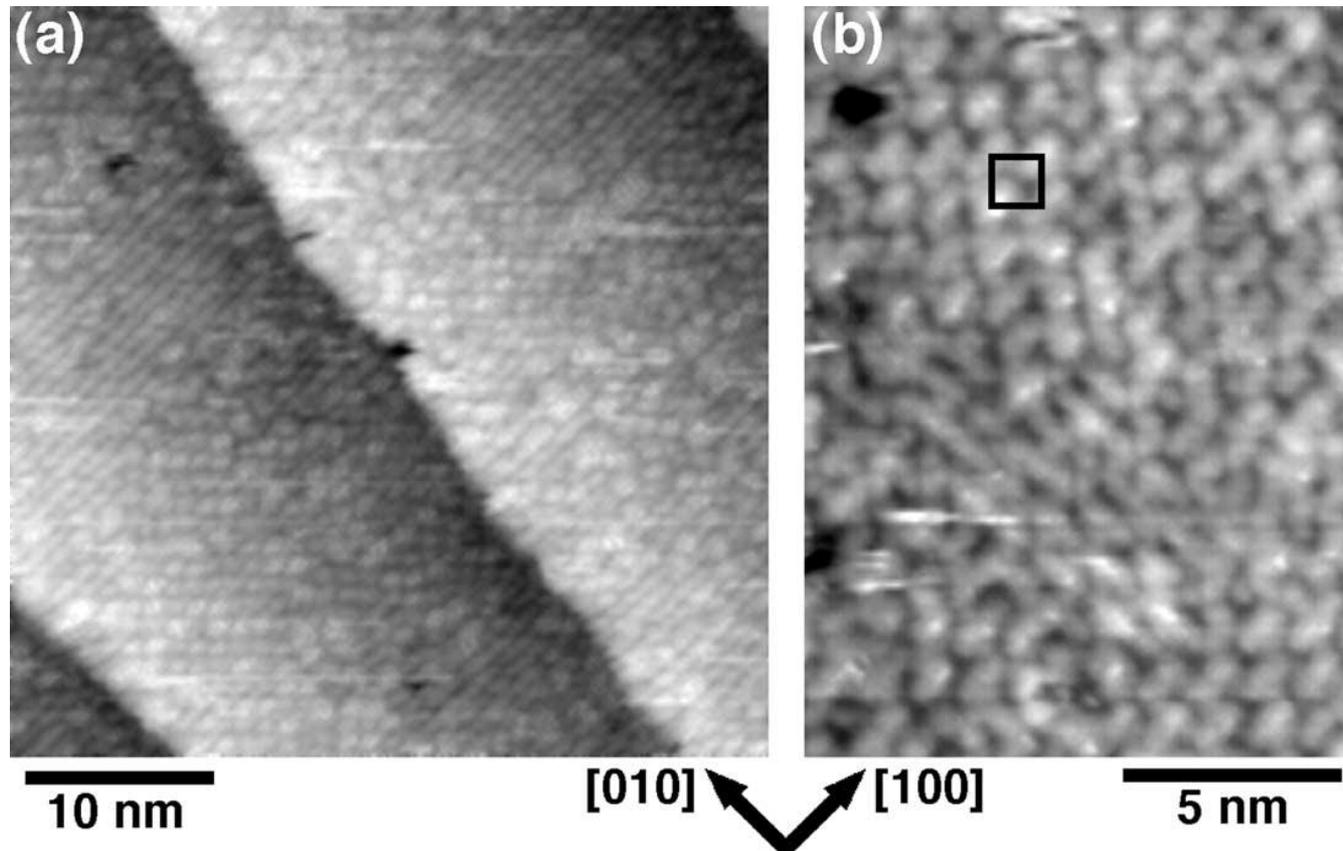


# (2x1) surface reconstruction



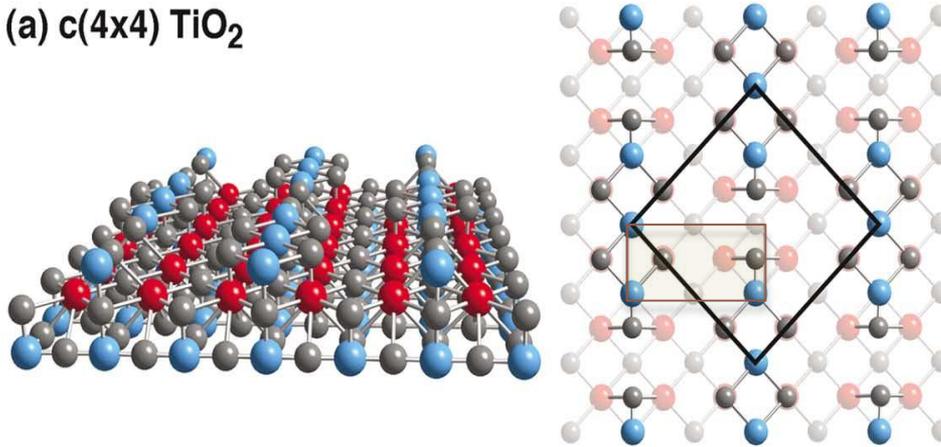
# c(4x4) surface reconstruction

---

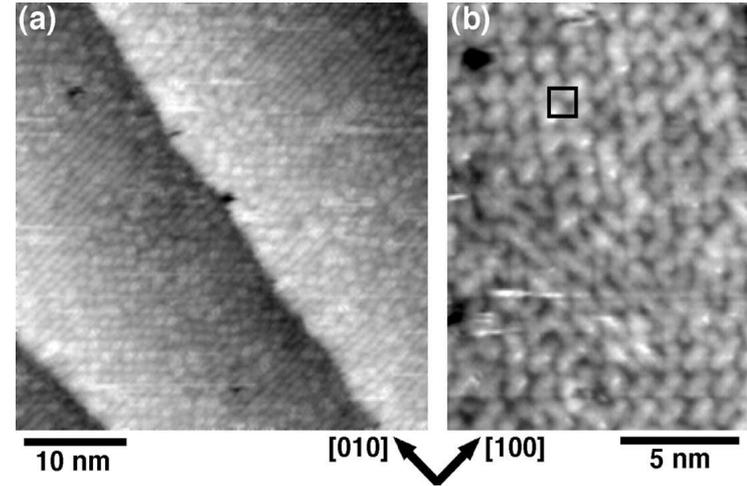
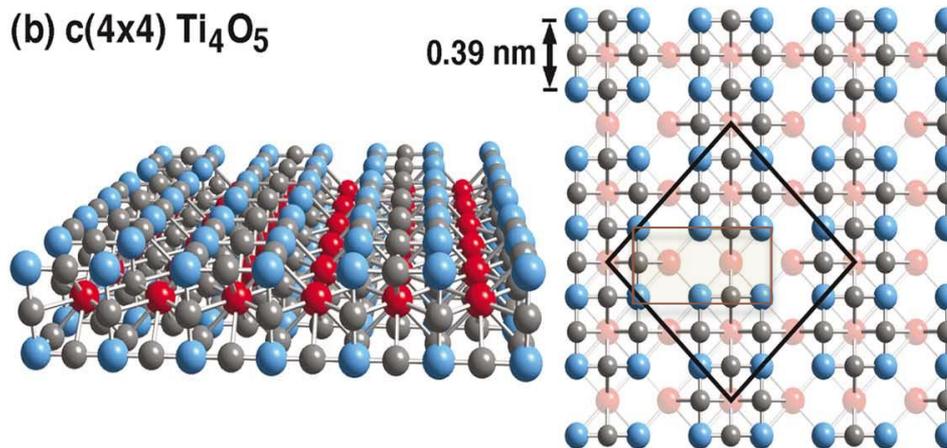


# c(4x4) surface reconstruction

(a) c(4x4) TiO<sub>2</sub>



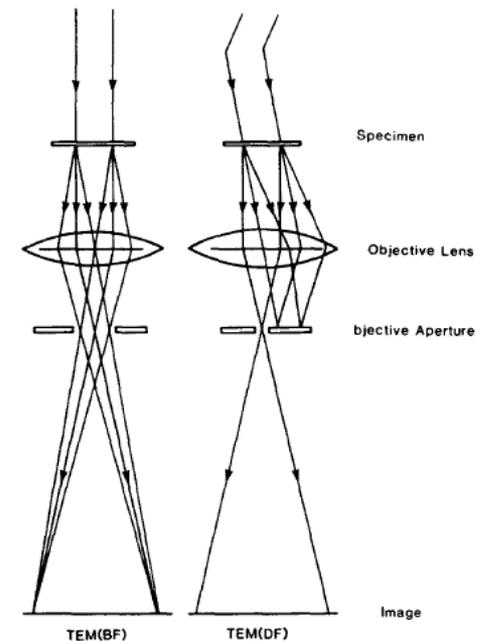
(b) c(4x4) Ti<sub>4</sub>O<sub>5</sub>



# Introduction TEM

---

- ▶ **Bright field mode**
  - ▶ Resolutions of angstroms
  - ▶ Imaging directly transmitted beam
- ▶ **Dark field TEM**
  - ▶ Incident beam tilted
  - ▶ Diffraction beam imaged
  - ▶ Crystal defect sensitivity



# TEM: phase contrast of surfaces

---

- ▶ **Primary contrast mechanism**
  - ▶ Phase of incident electron wave is modified by distribution of electrostatic potential
  - ▶ If crystal is perfect, 100 nm thick one can realign the sample to see surface
  - ▶ Surface steps, absorbed atoms or surface reconstructions visible if there are no bulk defects
- ▶ **Surface structural variations obscured by strong scattering in the bulk crystal**



# TEM: Dark field images with surface layer diffraction

---

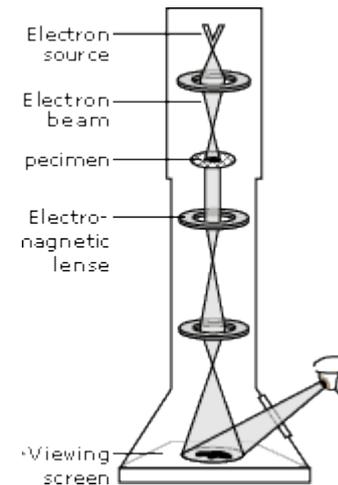
- ▶ Need different periodicity of the surface compared to bulk
- ▶ Advantage is that it is relative insensitive to surface contaminations
- ▶ Images are very weak
  - ▶ Long exposure times: drift
  - ▶ Low resolution
  - ▶ Details of structure not seen



# TEM: Nowadays

---

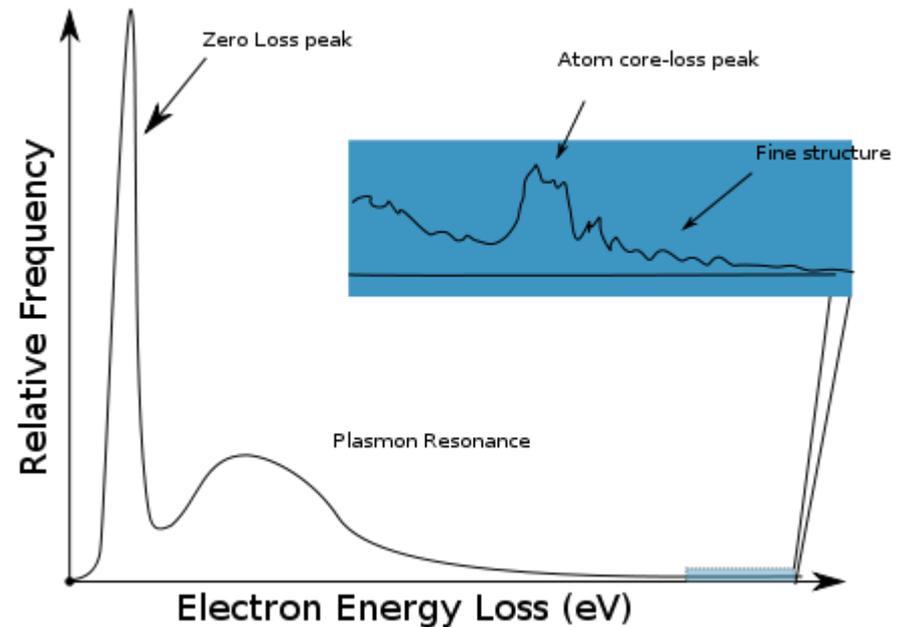
- ▶ **Contrast formation**
  - ▶ Bright field imaging mode
  - ▶ Electron diffraction contrast
  - ▶ Electron energy loss spectroscopy (EELS)
  - ▶ Phase contrast (HRTEM)
  
- ▶ **Diffraction**
  
- ▶ **3D imaging**



# Electron Energy Loss Spectroscopy

---

- ▶ Inelastic scattering
  - ▶ Phonon excitations
  - ▶ Inter and intra band transitions
  - ▶ Plasmon excitations
  - ▶ *Inner shell ionizations*
    - ▶ Type of atoms
    - ▶ Number of atoms
- ▶ Scattering angle
  - ▶ Dispersion relation
- ▶ Thickness measurements

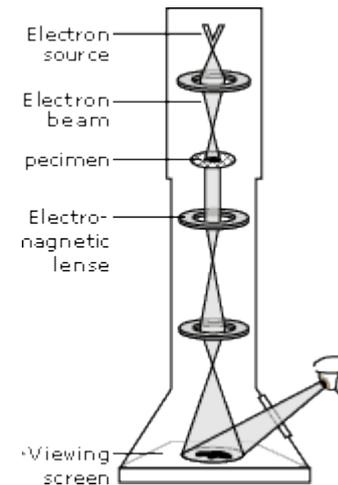
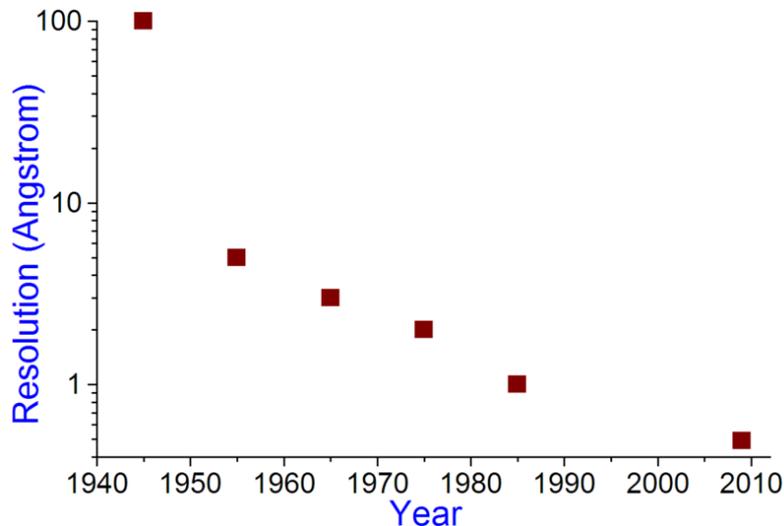


# Transmission Electron Microscopy

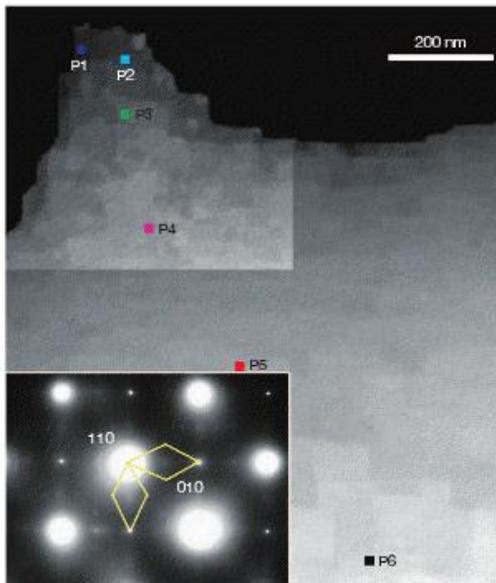
---

## ▶ Limitations

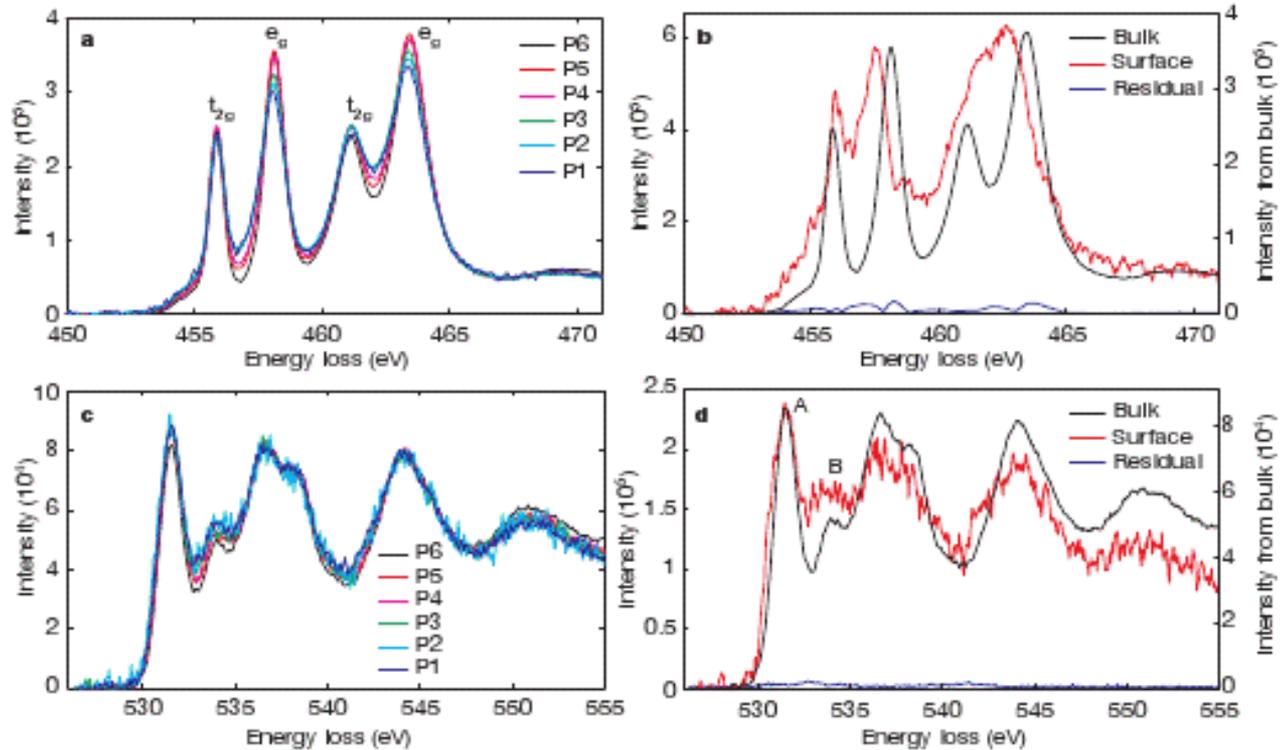
- ▶ Extensive sample preparation
- ▶ Possible changing of the sample during prep
- ▶ Small field of view
- ▶ Sample damage due to beam
- ▶ Resolution limits



# c(4x2): EELS



c(4x2)



# c(4x2): EELS

